

PCN Number:	20160713001	PCN Date:	07/13/2016
Title:	Qualification of AIZU as an additional Wafer Fab Site option for select devices in HPA07 Technology		
Customer Contact:	<u>PCN Manager</u>	Dept:	Quality Services
Proposed 1st Ship Date:	10/13/2016	Estimated Sample Availability:	Date provided at sample request.
Change Type:			
<input type="checkbox"/> Assembly Site	<input type="checkbox"/> Assembly Process	<input type="checkbox"/> Assembly Materials	
<input type="checkbox"/> Design	<input type="checkbox"/> Electrical Specification	<input type="checkbox"/> Mechanical Specification	
<input type="checkbox"/> Test Site	<input type="checkbox"/> Packing/Shipping/Labeling	<input type="checkbox"/> Test Process	
<input type="checkbox"/> Wafer Bump Site	<input type="checkbox"/> Wafer Bump Material	<input type="checkbox"/> Wafer Bump Process	
<input checked="" type="checkbox"/> Wafer Fab Site	<input type="checkbox"/> Wafer Fab Materials	<input type="checkbox"/> Wafer Fab Process	
	<input type="checkbox"/> Part number change		

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of its AIZU fabrication facility as an additional Wafer Fab source for the selected devices listed in "Product Affected" section.

Current Site			Additional Site		
Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter
DP1DM5	HPA07	200mm	AIZU	HPA07	200mm

Reason for Change:

Continuity of supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Current

Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City
DP1DM5	DM5	USA	Richardson

New

Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City
AIZU	CU2	JPN	Aizuwakamatsu-shi

Sample product shipping label (not actual product label):

TEXAS INSTRUMENTS
 MADE IN: Malaysia
 2DC: 2Q:
 MSL 2 / 260C / 1 YEAR SEAL DT
 MSL 1 / 235C / UNLIM 03/29/04
 OPT:
 ITEM: 39
LBL: 5A (L)T0:1750

(1P) SN74LS07NSR
 (Q) 2000 (D) 0336
 (31T) LOT: 3959047MLA
 (4W) TKY (1T) 7523483SI2
 (P)
 (2P) REV: 0033317
 (20L) CSO: SHE (21L) CCO: USA
 (22L) ASO: MLA (23L) ACO: MYS

Product Affected Group:

INA300AIDSQR	INA300AIDSQT
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Qualification Report
INA300AIDSQR/T in AIZU fab
Approve Date 07-Jul-2016

Product Attributes

Attributes	Qual Device: INA300AIDSQR	QBS Process Reference: CD3248B0YFFR	QBS Package Reference: DRV401AIRGW	QBS Package Reference: SN75DP122ARTQ	QBS Package Reference: TLVDA321RHBR	QBS Package Reference: TPA2005D1DRB	QBS Package Reference: TP551217DSCR_RFAB	QBS Package Reference: TP551217DSC_UMC	QBS Package Reference: TPS51621RHA
Assembly Site	CLARKAT	CLARKAT	CLARKAT	CLARKAT	CLARKAT	CLARKAT	CLARKAT	CLARKAT	CLARKAT
Package Family	WSON	WCSP	VQFN	VQFN	VQFN	VSON	WSON	WSON	VQFN
Wafer Fab Supplier	AIZU	AIZU	DMOS5	FFAB	DMOS5	FR-BIP-1	RFAB	UMC-8A8	DFAB
Wafer Process	50HPA07HV	50HPA07HV	50HPA07	50BICOM3XL	1833C05X4	3370A12X3	LBC7	LBC7	LBC4

- QBS: Dual by Similarity
- Qual Device INA300AIDSQR is qualified at LEVEL2-260C

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: INA300AIDSQR	QBS Process Reference: CD3248B0YFFR	QBS Package Reference: DRV401AIRGW	QBS Package Reference: SN75DP122ARTQ	QBS Package Reference: TLVDA321RHBR	QBS Package Reference: TPA2005D1DRB	QBS Package Reference: TP551217DSCR_RFAB	QBS Package Reference: TP551217DSC_UMC	QBS Package Reference: TPS51621RHA
AC	Autoclave 121C	96 Hours	-	-	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0	3/228/0	3/231/0
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass	-	-	-	-	-	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	-	-	-	-	-	-	-
HBM	ESD - HBM	2500 V	1/3/0	2/12/0	-	-	-	-	-	-	-
CDM	ESD - CDM	1500 V	1/3/0	1/3/0	-	-	-	-	-	-	-
HTOL	Life Test, 150C	300 Hours	1/77/0	3/231/0	-	-	-	-	-	-	-
HTSL	High Temp. Storage bake, 170C	420 Hours	-	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0
LU	Latch-up	Per JESD78	1/6/0	3/18/0	-	-	-	-	-	-	-
SBS	Bump-shear	-	-	3/150/0	-	-	-	-	-	-	-
TC	Temperature Cycle, -55/125C	500 Cycles	-	3/231/0	-	-	-	-	-	-	-
TC	Temperature Cycle, -55/150C	500 Cycles	1/77/0	-	3/230/0	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0
UHAST	Unbiased HAST 130C/85%RH	96 Hours	-	3/231/0	-	-	-	-	-	-	-

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/420 Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles
Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>
Green/Pb-free Status:
Qualified Pb-Free (SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
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